

54ABT16646 16-Bit Transceivers and Registers with TRI-STATE Outputs



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General Description

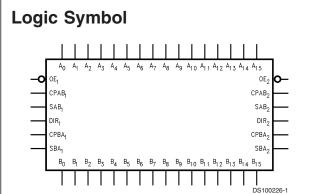
The 'ABT16646 consists of bus transceiver circuits with TRI-STATE, D-type flip-flops, and control circuitry arranged for multiplexed transmission of data directly from the input bus or from the internal registers. Data on the A or B bus will be clocked into the registers as the appropriate clock pin goes to a high logic level. Control \overrightarrow{OE} and direction pins are provided to control the transceiver function. In the transceiver mode, data present at the high impedance port may be stored in either the A or the B register or in both. The select controls can multiplex stored and real-time (transparent mode) data. The direction control determines which bus will receive data when the enable control \overrightarrow{OE} is Active LOW. In the isolation mode (control \overrightarrow{OE} HIGH), A data may be stored in the B register and/or B data may be stored in the A register.

Features

- Independent registers for A and B buses
- Multiplexed real-time and stored data
- A and B output sink capability of 48 mA, source capability of 24 mA
- Guaranteed latchup protection
- High impedance glitch free bus loading during entire power up and power down cycle
- Nondestructive hot insertion capability
- Standard Microcircuit Drawing (SMD) 5962-9450202

Ordering Code

Military	Package	Package Description	
	Number		
54ABT16646W-QML	WA56A	56-Lead Cerpack	



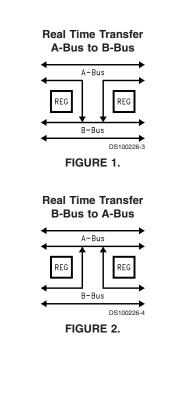
Pin Names	Description
A ₀ -A ₁₅	Data Register A Inputs/
	TRI-STATE Outputs
B ₀ -B ₁₅	Data Register B Inputs/
	TRI-STATE Outputs
CPAB _n , CPBA _n	Clock Pulse Inputs
SAB _n , SBA _n	Select Inputs
0E _n	Output Enable Input
DIR	Direction Control Input



Connection Diagram

	. <u>.</u>			
		∇		_
dir ₁ —	1		56	- 0E1
СРАВ ₁ —	2		55	— СРВА ₁
sab ₁ —	3		54	— SBA ₁
gnd 🗕	4		53	— GND
A ₀ —	5		52	— в _о
A1 —	6		51	— в ₁
v _{cc} —	7		50	— v _{cc}
A ₂ —	8		49	— в ₂
A3 —	9		48	— B ₃
A4 —	10		47	— B ₄
GND —	11		46	— GND
A ₅ —	12		45	— в ₅
A ₆ —	13		44	— B ₆
A ₇ —	14		43	— В ₇
A ₈ —	15		42	— в ₈
A ₉ —	16		41	— В ₉
A ₁₀ —	17		40	— B ₁₀
GND —	18		39	— GND
A ₁₁ —	19		38	— B _{1 1}
A ₁₂ —	20		37	— В _{1 2}
A ₁₃ —	21		36	— B _{1 3}
v _{cc} —	22		35	– v _{cc}
A ₁₄ —	23		34	— В ₁₄
A ₁₅ —	24		33	— B ₁₅
gnd —	25		32	— GND
sab ₂ —	26		31	— SBА ₂
срав ₂ —	27		30	— СРВА ₂
DIR ₂ —	28		29	- 0E2
			P (
			DS	100226-2





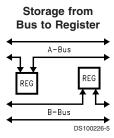


FIGURE 3.

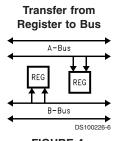


FIGURE 4.

Function Table

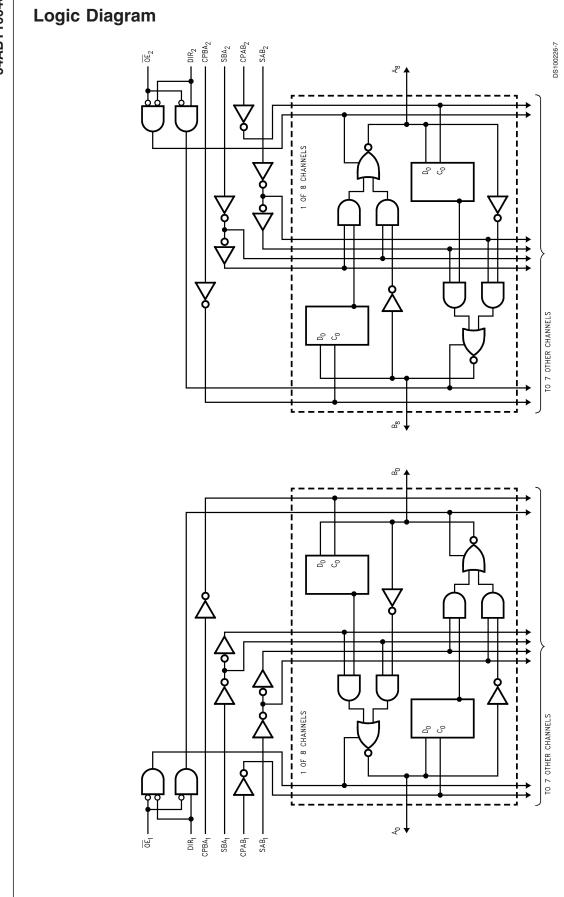
Inputs						Data I/O (Note 1)		Output Operation Mode	
\overline{OE}_1	DIR ₁	CPAB ₁	CPBA ₁	SAB ₁	SBA ₁	A ₀₋₇	B ₀₋₇		
Н	Х	H or L	H or L	Х	Х			Isolation	
Н	Х	Ν	Х	Х	Х	Input	Input	Clock An Data into A Register	
Н	Х	Х	Ν	Х	Х			Clock Bn Data Into B Register	
L	Н	Х	Х	L	Х			An to Bn—Real Time (Transparent Mode)	
L	Н	Ν	Х	L	Х	Input	Output	Clock An Data to A Register	
L	Н	H or L	Х	Н	Х			A Register to Bn (Stored Mode)	
L	Н	Ν	Х	Н	Х			Clock An Data into A Register and Output to Bn	
L	L	Х	Х	Х	L			Bn to An—Real Time (Transparent Mode)	
L	L	Х	Ν	Х	L	Output	Input	Clock Bn Data into B Register	
L	L	Х	H or L	Х	Н			B Register to An (Stored Mode)	
L	L	Х	Ν	Х	Н			Clock Bn into B Register and Output to An	

H = HIGH Voltage Level X = Immaterial

L = LOW Voltage Level N = LOW-to-HIGH Transition.

Note 1: The data output functions may be enabled or disabled by various signals at the $\overline{\text{OE}}$ and DIR inputs. Data input functions are always enabled; i.e., data at the bus pins will be stored on every LOW-to-HIGH transition of the appropriate clock inputs. Also applies to data I/O (A and B: 8-15) and #2 control pins.

54ABT16646



54ABT16646

Absolute Maximum Ratings (Note 2)

Storage Temperature	−65°C to +150°C
Ambient Temperature under Bias	–55°C to +125°C
Junction Temperature under Bias	
Ceramic	–55°C to +175°C
V _{CC} Pin Potential to	
Ground Pin	-0.5V to +7.0V
Input Voltage (Note 3)	-0.5V to +7.0V
Input Current (Note 3)	-30 mA to +5.0 mA
Voltage Applied to Any Output	
in the Disable or	
Power-Off State	-0.5V to +5.5V
in the HIGH State	–0.5V to V $_{\rm CC}$
Current Applied to Output	
in LOW State (Max)	twice the rated I_{OL} (mA)
DC Latchup Source Current	–500 mA

Over Voltage Latchup (I/O)

Recommended Operating Conditions

Free Air Ambient Temperature	
Military	–55°C to +125°C
Supply Voltage	
Military	+4.5V to +5.5V
Minimum Input Edge Rate	$(\Delta V / \Delta t)$
Data Input	50 mV/ns
Enable Input	20 mV/ns
Clock Input	100 mV/ns

Note 2: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 3: Either voltage limit or current limit is sufficient to protect inputs.

DC Electrical Characteristics

Symbol	Parameter		ABT16646			V _{cc}	Conditions	
		Min	Тур	Мах				
V _{IH}	Input HIGH Voltage	2.0			V		Recognized HIGH Signal	
V _{IL}	Input LOW Voltage			0.8	V		Recognized LOW Signal	
V _{CD}	Input Clamp Diode Voltage			-1.2	V	Min	I _{IN} = -18 mA (Non I/O Pins)	
V _{OH}	Output HIGH Voltage 54ABT 54ABT	2.5 2.0					$I_{OH} = -3 \text{ mA}, (A_n, B_n)$ $I_{OH} = -24 \text{ mA}, (A_n, B_n)$	
V _{OL}	Output LOW Voltage 54ABT	2.0		0.55	V	Min	$I_{OL} = 48 \text{ mA}, (A_n, B_n)$	
V _{ID}	Input Leakage Test	4.75			V	0.0	$I_{ID} = 1.9 \ \mu$ A, (Non-I/O Pins) All Other Pins Grounded	
I _{IH}	Input HIGH Current			5	μA	Max	$V_{IN} = 2.7V$ (Non-I/O Pins) (Note 5) $V_{IN} = V_{CC}$ (Non-I/O Pins)	
I _{BVI}	Input HIGH Current Breakdown Test			7	μA	Max	V _{IN} = 7.0V (Non-I/O Pins)	
I _{BVIT}	Input HIGH Current Breakdown Test (I/O)			100	μA	Max	$V_{IN} = 5.5V (A_n, B_n)$	
IIL	Input LOW Current			-5	μΑ	Мах	$V_{IN} = 0.5V$ (Non-I/O Pins) (Note 5 $V_{IN} = 0.0V$ (Non-I/O Pins)	
I _{IH} + I _{OZH}	Output Leakage Current			50	μA	0V-5.5V	$V_{OUT} = 2.7V (A_n, B_n); \overline{OE} = 2.0V$	
$I_{IL} + I_{OZL}$	Output Leakage Current			-50	μA	0V-5.5V	$V_{OUT} = 0.5V (A_n, B_n); \overline{OE} = 2.0V$	
los	Output Short-Circuit Current	-100		-275	mA	Max	$V_{OUT} = 0V (A_n, B_n)$	
CEX	Output HIGH Leakage Current			50	μA	Max	$V_{OUT} = V_{CC} (A_n, B_n)$	
Izz	Bus Drainage Test			100	μA	0.0V	$V_{OUT} = 5.5V (A_n, B_n);$ All Others GND	
ссн	Power Supply Current			2.0	mA	Max	All Outputs HIGH	
CCL	Power Supply Current			60	mA	Max	All Outputs LOW	
ccz	Power Supply Current			2.0	mA	Max	Outputs TRI-STATE; All Others GND	
I _{сст}	Additional I _{CC} /Input			2.5	mA	Max	$V_1 = V_{CC} - 2.1V$ All Other Outputs at V_{CC} or GND	
ССD	Dynamic I _{CC} No Load (Note 5)			0.23	mA/MHz	Max	Outputs Open \overline{OE} , DIR, and SEL = GND, Non-I/O = GND or V _{CC} (Note 4) One Bit toggling, 50% duty cycle	

DC Electrical Characteristics (Continued)

Note 4: For 8-bit toggling, I_{CCD} < 1.4 mA/MHz. Note 5: Guaranteed but not tested.

Sym- bol	Parameter	Min	Мах	Units	V _{cc}	Conditions
						C_L = 50 pF, R_L = 500 Ω
V _{OLP}	Quiet Output Maximum Dynamic V _{OL}		1.0	V	5.0	$T_A = 25^{\circ}C$ (Note 6)
V _{OLV}	Quiet Output Minimum Dynamic V _{OL}		-1.5	V	5.0	$T_A = 25^{\circ}C$ (Note 6)

Note 6: Max number of outputs defined as (n). n – 1 data inputs are driven 0V to 3V. One output at LOW. Guaranteed, but not tested.

AC Electrical Characteristics

		54A	\BT			
		T _A = -55°C to +125°C				
Symbol Parameter		$V_{CC} = 4.$	5V–5.5V	Units		
		C _L = 5				
		Min	Max			
f _{max}	Max Clock Frequency	125		MHz		
t _{PLH}	Propagation Delay	1.0	6.9	ns		
t _{PHL}	Clock to Bus	1.0	7.7			
t _{PLH}	Propagation Delay	1.0	5.8	ns		
t _{PHL}	Bus to Bus	1.0	7.0			
t _{PLH}	Propagation Delay	1.0	7.1	ns		
t _{PHL}	SBA _n or SAB _n to A _n to B _n	1.0	7.2			
t _{PZH}	Enable Time	1.0	6.4	ns		
t _{PZL}	\overline{OE}_n to A_n or B_n	1.0	6.5			
t _{PHZ}	Disable Time	1.0	7.6	ns		
t _{PLZ}	\overline{OE}_n to A_n or B_n	1.0	6.5			
t _{PZH}	Enable Time	1.0	6.4	ns		
t _{PZL}	DIR _n to A _n or B _n	1.0	6.7			
t _{PHZ}	Disable Time	1.0	8.1	ns		
t _{PLZ}	DIR _n to A _n or B _n	1.0	7.1			

AC Operating Requirements

Symbol	Parameter	$ T_A = -55^{\circ} C_C = 4 C_L = $	Units	
		Min	Мах	
t _S (H)	Setup Time, HIGH	4.0		ns
t _S (L)	or LOW Bus to Clock			
t _H (H)	Hold Time, HIGH	0.5		ns
t _H (L)	or LOW Bus to Clock			
t _w (H)	Pulse Width,	4.3		ns
t _{vv} (L)	HIGH or LOW			

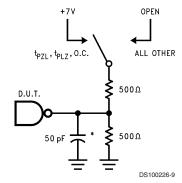
Capacitance

Symbol	bol Parameter		Units	Conditions
	Input Canaditanaa	E	ъĘ	$T_{A} = 25^{\circ}C$
	Input Capacitance	5	p⊢ _	$V_{CC} = 0V$ (non I/O pins)
C _{I/O} (Note 7)	Output Capacitance	11	pF	$V_{\rm CC} = 5.0 V (A_{\rm n}, B_{\rm n})$

Capacitance (Continued)

Note 7: $C_{I/O}$ is measured at frequency, f = 1 MHz, per MIL-STD-883B, Method 3012.

AC Loading



*Includes jig and probe capacitance

FIGURE 5. Standard AC Test Load

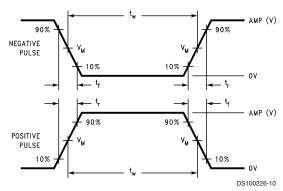


FIGURE 6. $V_M = 1.5V$ Input Pulse Requirements

Ampli- tude	Rep. Rate	t _w	t _r	t _f	
3V	1 MHz	500 ns	2.5 ns	2.5 ns	

FIGURE 7. Test Input Signal Requirements

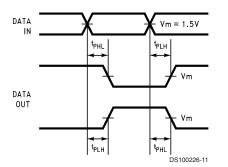
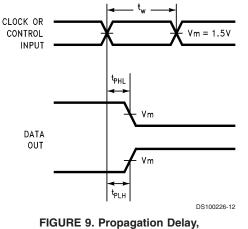


FIGURE 8. Propagation Delay Waveforms for Inverting and Non-Inverting Functions





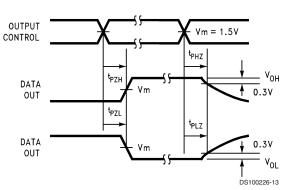
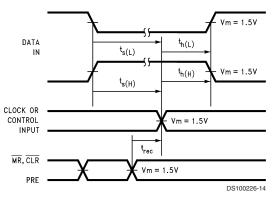
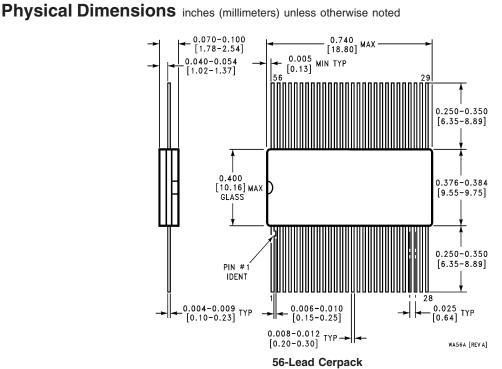
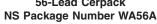


FIGURE 10. TRI-STATE Output HIGH and LOW Enable and Disable Times









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